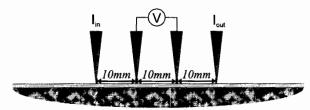
Final Exam

FYSS335 Micro- and nanofabrication

Friday 19.2.2010

- 1. Explain briefly
 - (a) Comformation, step coverage and bottom coverage
 - (b) Sputtering
 - (c) Growth of silicon by "Float Zone" (FZ) -method
 - (d) Spin coating
 - (e) Laser ablation
 - (f) 'top-down' vs. 'bottom-up' fabrication methods
- 2. One evaporates an Al/Mn-alloy film on a 15.6 cm diameter Si wafer by using resistive heating of 1:1-mixture of aluminium (Al) and Manganese (Mn) inside a UHV chamber. Metals are heated to a constant temperature of 1200°C, yielding a high enough vapour pressure $P_v > 10^{-2}$ mbar for both metals to be evaporated. After the evaporation, the film thickness was measured to be 80 nm and the electrical four probe measurement of the film, by using the probe configuration shown below, yielded 302 mV with 60 mA current. Calculate the sheet resistance and the resistivity of the film and explain by formulas, i.e. by calculating, why the resistivity deviates from the expected resistivity of the 1:1-mixture of the two metals: $\rho_{\rm Al} \approx 2.7 \cdot 10^{-8} \ \Omega {\rm m}$ and $\rho_{\rm Mn} \approx 185 \cdot 10^{-8} \ \Omega {\rm m} \Longrightarrow \rho_{1:1} \approx 93.8 \cdot 10^{-8} \ \Omega {\rm m}$.



- 3. Explain in detail the general principle of deposition of thin films by Plasma Enhanced Chemical Vapor Deposition (PECVD) using RF-plasma inside a planar electrode station, where another electrode is grounded and another is capacitively coupled to RF-source. Explain also the tensile and compressive stress, and how can the stress of the formed film be controlled in PECVD processes.
- 4. Aluminum oxide (Al₂O₃ also known as alumina) is a highly stable coating material in many industrial applications. It is produced by (LP-/AP-)CVD via reaction:

$$2AlCl_3 + 3H_2 + 3CO_2 \longrightarrow Al_2O_3 + 3CO + 6HCl$$

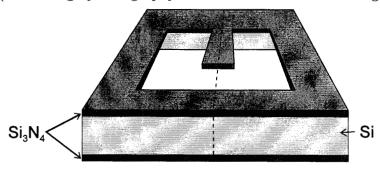
Typical recipe is of the form: $T\approx 1050^{\circ}C$, P=10 Torr, and gas flows: $AlCl_3=700$ sccm, $H_2=3300$ sccm and $CO_2=1200$ sccm.

(a) By using the recipe above, what is the theoretical maximum deposition rate of Al_2O_3 , i.e., thickness growth rate, if the total deposition area (quartz tube and wafers) is 2 m²? Density of aluminum oxide is 3.965 g/cm³ and gases can be treated as ideal gases.

(b) To characterize process more, the deposition rate was measured in slightly different temperatures. The obtained data is shown below and the activation energy for the chemical reaction above is known to be 704 meV $\approx 1.13 \cdot 10^{-19}$ J. Is the process either transport limited or reaction limited?

Temperature (°C)	Rate /(Rate at 1050°C)
882	0.841
950	0.904
1050	1.000
1114	1.061

5. Thin Si₃N₄ cantilevers could be used for example as a flow meter in microfluidistic structures. This is realized, e.g., by letting the fluid to flow through a tiny opening in a Si₃N₄ covered silicon chip with Si₃N₄ cantilever attached on a side of the opening and by measuring the bending of the cantilever (see figure below). Develop a process, starting from a plain silicon wafer, to fabricate this structure, shown below. Describe process steps needed. (Patterning by lithography needs not to be described in great detail)





view from up



view from down



Cross-section along the dashed line on the 3D image

Some of these might be useful:

$$F = \frac{1}{4}n_0\langle v \rangle \qquad \langle v \rangle = \sqrt{\frac{8k_BT}{\pi m}} \qquad R_{\rm sheet} = \frac{V}{I} \frac{\pi}{\ln 2}$$

$$\cos(x) = 1 - \frac{x^2}{2!} + \frac{x^4}{4!} - \dots \qquad \lambda = \frac{k_BT}{\sqrt{2P\pi a^2}} \qquad \langle v^2 \rangle = \frac{3k_BT}{m}$$

$$\sin(x) = x - \frac{x^3}{3!} + \frac{x^5}{5!} - \dots \qquad F = \frac{P_v}{\sqrt{2\pi M k_B T}}$$

$$P_v = \frac{1}{3}mn_0\langle v^2 \rangle \qquad \sigma = \frac{E_S t_S^2}{6t_F(1 - \nu_S)} \left(\frac{1}{R} - \frac{1}{R_0}\right) \qquad \rho = \frac{V}{I} 2\pi s$$

$$V = -\frac{k_BT}{2e} \ln\left(\frac{T_e m_i}{T_i m_e}\right) \qquad t = \frac{d^2}{2DC_sV} + \frac{d}{kC_sV} \qquad \text{Rate} = Z(T) \exp\left(-\frac{E_a}{k_BT}\right)$$

$$F = -D\frac{\partial C}{\partial x} \qquad E_{\text{Si}} = 190 \text{ GPa} \qquad \rho_{\text{Si}} = 2.33 \text{ g/cm}^3 \qquad \nu_{\text{Si}} = 0.27$$

$$k_B = 1.3806503 \cdot 10^{-23} \text{ J/K} \qquad \pi = 3.141592654 \qquad \rho_{\text{Al}} \approx 2.7 \cdot 10^{-8} \Omega \text{m}$$

$$\rho_{\text{Si3N4}} \approx 3.1 \text{ g/cm}^3 \qquad \text{AtomicMassConstant} = 1.66053873 \cdot 10^{-27} \text{ kg}$$

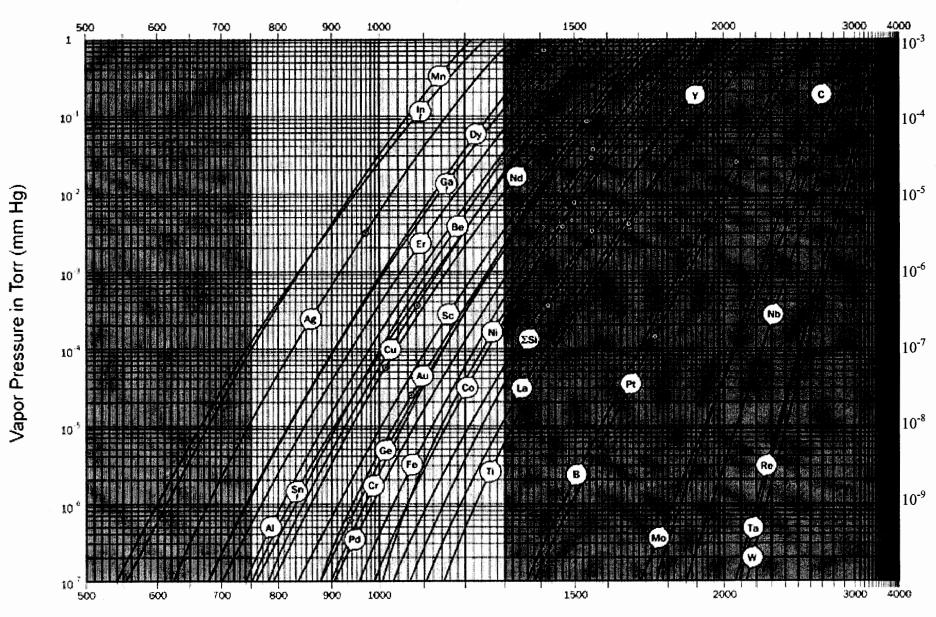
$$\text{AvogadroConstant} = N_A = 6.02214199 \cdot 10^{23} \qquad \nu_{\text{Si}} = 0.27$$

$$\text{ElectronMass} = 9.10938188 \cdot 10^{-31} \text{ kg} \qquad \text{ElectronCharge} = 1.602176462 \cdot 10^{-19} \text{ C}$$

$$1 \text{ Torr} = 133.3 \text{ Pa} \qquad \text{R.I.}_{\text{Si3N4}} \approx 2.05 \qquad \rho_{\text{Mn}} \approx 185 \cdot 10^{-8} \Omega \text{m}$$

$$R_{\text{(Molar gas constant)}} = 8.314472 \text{ J/(Kmol)}$$

	1A																	8A
I	1																	2
	Н														٠.			He
ŀ	1.0079	2A	ı										3A	4A	5A	6A	7A 9	4.0026 10
١	3 Li	Be											5 B	6 C	Ń	8	F	Ne
ı	6.941	9.0122											10.811	12.0107	14.0067	15.999	18.9984	20.1797
Ì	11	12											13	14	15	16	17	18
١	Na	Mg											Al	Si	Р	s	CI	Ar
ı	22.9898	24.305	3B	4B	5B	6B_	7B		— 8B —		1B	2B	26.9815	28.0855	30.9738	32.065	35.453	39.948
	19	20	21	22	23	24	25	26	27	28	29	30	31	32	33	34	35	36
-	K	Ca	Sc	Ti	V	Cr	Mn	Fe	Со	Ni	Cu	Zn	Ga	Ge	As	Se	Br	Kr
ı	39.098	40.078	44.9559	47.867	50.9415	51.9961	54.9380	55.845	58.9332	58.6934	63.546	65.38	69.723	72.64	74.9216	78.96	79.904	83,798
V	37	38	39	40	41	42	43	44	45	46	47	48	49	50	51	52	53	54
	Rb 85,468	Sr 87.62	Y 88.9058	Zr 91,224	Nb 92.906	Mo 95,96	TC [98]	Ru 101.07	Rh 102.905	Pd 106.42	Ag 107.868	Cd 112.411	in 114,818	Sn 118.710	Sb 121.760	Te	26.9045	Xe 131.293
ı	55	56	57-71	72	73	74	75	76	77	78	79	80	81	82	83	84	85	86
ı	Cs	Ba		Hf	Та	w	Re	Os	lr	Pt	Au	Hg	TI	Pb	Bi	Po	At	Rn
	132.905	137.33	Lanthanides	178.49	180.948	183.84	186.207	190.23	192.217	195.084	196.9666	200.59	204.3833	207.2	208.9804	[209]	[210]	[222]
ı	87	88	89-103	104	105	106	107	108	109	110	111	112	113	114	115	116	117	118
١	Fr	Ra		Rf	Db	Sg	Bh	Hs	Mt	Ds	Rg	Uub	Uut	Uuq	Uup	Uuh	Uus	Uuo
Į	223	[226]	Actinides	[267]	[268]	[271]	[272]	[270]	[276]	[281]	[280]	[285]	[284]	[289]	[288]	[293]	[294]	[294]
													-					
	Lanthanides		57	58	59	60	61	62	63	64	65	66	67	68	69	70	71	
			La	Ce	Pr	Nd	Pm	Sm	Eu	Gd	Tb	Dy 162,500	Но	Er	Tm	Yb	Lu	
				400 00547	440 440	440.00766	444 242	[4.4E]									472 OE4	
				138.90547	140.116	140.90765 Q1	144.242	[145] 93	150.36 Q4	151.964	157.25	158.92535		164.93032 QQ	167.259	168.93421	173.054	174.9668
		Actinide	e	138.90547 89 AC	90 Th	91 Pa	144.242 92	93 Np	94 Pu	95 Am	96 Cm	97 Bk	98 Cf	99 Es	100 Fm	168.93421 101 Md	173.054 102 No	174.9668 103 Lr



Temperature in Degrees Centigrade